

General Description

The 70N03 is the highest performance trench N-ch MOSFETs with extreme high cell density, which provide excellent R_{DS(on)} and gate charge for most of the synchronous buck converter applications.

The 70N03 meet the RoHS and Green Product requirement, 100% EAS guaranteed with full function reliability approved.

Features

- Advanced high cell density Trench technology
- Super Low Gate Charge
- Excellent CdV/dt effect decline
- 100% avalanche tested
- Green Device Available

Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
V _{DS}	Drain-Source Voltage	30	V
V _{GS}	Gate-Source Voltage	±20	V
I _D @T _C =25°C	Continuous Drain Current ¹	70	A
I _D @T _C =100°C	Continuous Drain Current ¹	50	A
I _{DM}	Pulsed Drain Current ²	170	A
EAS	Single Pulse Avalanche Energy ³	85	mJ
I _{AS}	Avalanche Current	45	A
P _D @T _C =25°C	Total Power Dissipation	65	W
T _{STG}	Storage Temperature Range	-55 to 175	°C
T _J	Operating Junction Temperature Range	-55 to 175	°C

Thermal Data

Symbol	Parameter	Typ.	Max.	Unit
R _{θJA}	Thermal Resistance Junction-ambient ¹	---	70	°C/W
R _{θJC}	Thermal Resistance Junction -Case ¹	---	2	°C/W

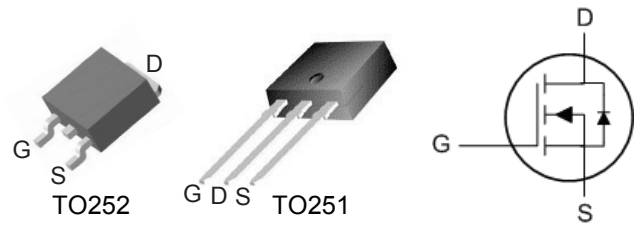
Product Summary

BVDSS	R _{DS(on)}	ID
30V	7mΩ	70A

Applications

- High Frequency Point-of-Load Synchronous Buck Converter for MB/NB/UMPC/VGA
- Networking DC-DC Power System
- Load Switch

TO252 / TO251 Pin Configuration



N-Ch 30V Fast Switching MOSFETs

Electrical Characteristics ($T_J=25\text{ }^\circ\text{C}$, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu A$	30	---	---	V
$\Delta BV_{DSS}/\Delta T_J$	BVDSS Temperature Coefficient	Reference to $25\text{ }^\circ\text{C}$, $I_D=1mA$	---	6.5	---	MV/ $^\circ\text{C}$
$R_{DS(ON)}$	Static Drain-Source On-Resistance ²	$V_{GS}=10V, I_D=20A$	---	5.3	7	m Ω
		$V_{GS}=4.5V, I_D=20A$	---	7.5	11.5	
$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS}=V_{DS}, I_D=250\mu A$	1.0	1.5	3	V
$\Delta V_{GS(th)}$	$V_{GS(th)}$ Temperature Coefficient		---	5.08	---	mV/ $^\circ\text{C}$
I_{DSS}	Drain-Source Leakage Current	$V_{DS}=20V, V_{GS}=0V, T_J=25\text{ }^\circ\text{C}$	---	---	1	μA
		$V_{DS}=20V, V_{GS}=0V, T_J=150\text{ }^\circ\text{C}$	---	---	10	
I_{GSS}	Gate-Source Leakage Current	$V_{GS}=\pm 20V, V_{DS}=0V$	---	---	± 100	nA
g_{fs}	Forward Transconductance	$V_{DS}=10V, I_D=15A$	---	29	---	S
R_g	Gate Resistance	$V_{DS}=0V, V_{GS}=0V, f=1MHz$	---	1.7	3.4	Ω
Q_g	Total Gate Charge	$V_{DS}=10V, V_{GS}=5V, I_D=30A$	---	16.6	25.5	nC
Q_{gs}	Gate-Source Charge		---	8.1	---	
Q_{gd}	Gate-Drain Charge		---	4.7	---	
$T_{d(on)}$	Turn-On Delay Time	$V_{DD}=10V, V_{GS}=10V, R_G=3.3\Omega$ $I_D=30A$	---	13	---	ns
T_r	Rise Time		---	6.7	---	
$T_{d(off)}$	Turn-Off Delay Time		---	22.5	---	
T_f	Fall Time		---	10.1	---	
C_{iss}	Input Capacitance	$V_{DS}=20V, V_{GS}=0V, f=1MHz$	---	2211	---	pF
C_{oss}	Output Capacitance		---	515	---	
C_{rss}	Reverse Transfer Capacitance		---	174	---	

Diode Characteristics

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
I_S	Continuous Source Current ¹	$V_G=V_D=0V$, Force Current	---	27	---	A
I_{SM}	Pulsed Source Current ²		---	---	100	A
V_{SD}	Diode Forward Voltage ²	$V_{GS}=0V, I_S=1A, T_J=25\text{ }^\circ\text{C}$	---	---	1.3	V

Note :

- 1.The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2.The data tested by pulsed , pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$
- 3.The EAS data shows Max. rating . The test condition is $V_{DD}=30V, V_{GS}=10V, L=0.1mH, I_L=12A$